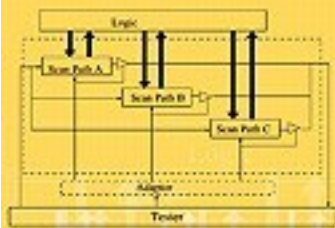


Power-Constrained Testing of Vlsi Circuits

Power-Constrained Testing of VLSI Circuits

by
Nicola Nicolici and Bashir M. Al-Hashimi



Kluwer Academic Publishers

[Power-Constrained Testing of Vlsi Circuits 下载链接1](#)

著者:Nicolici, Nicola/ Al-Hashimi, Bashir

出版者:Kluwer Academic Pub

出版时间:

装帧:HRD

isbn:9781402072352

作者介绍:

目录:

[Power-Constrained Testing of Vlsi Circuits_ 下载链接1](#)

标签

评论

[Power-Constrained Testing of Vlsi Circuits_ 下载链接1](#)

书评

[Power-Constrained Testing of Vlsi Circuits_ 下载链接1](#)